



CAN TRANSCEIVER

FEATURES

- Drop-In Improved Replacement for the PCA82C250 and PCA82C251
- Bus-Fault Protection of ±36 V
- Meets or Exceeds ISO 11898
- Signaling Rates⁽¹⁾ Up to 1 Mbps
- High Input Impedance Allows up to 120 SN65HVD251 Nodes on a Bus
- Bus Pin ESD Protection Exceeds 14 kV HBM
- Unpowered Node Does Not Disturb the Bus
- Low-Current Standby Mode 200 μA Typical
- Thermal Shutdown Protection
- Glitch-Free Power-Up and Power-Down Bus Protection For Hot-Plugging
- DeviceNet Vendor ID # 806
- (1) The signaling rate of a line is the number of voltage transitions that are made per second expressed in bps (bits per second).

APPLICATIONS

- CAN Data Buses
- Industrial Automation
 - DeviceNet™ Data Buses
 - Smart Distributed Systems (SDS™)
- SAE J1939 Standard Data Bus Interface
- NMEA 2000 Standard Data Bus Interface
- ISO 11783 Standard Data Bus Interface

DESCRIPTION

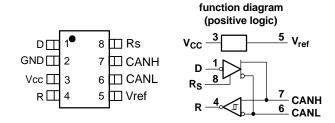
The SN65HVD251 is intended for use in applications employing the Controller Area Network (CAN) serial communication physical layer in accordance with the ISO 11898 Standard. The SN65HVD251 provides differential transmit capability to the bus and differential receive capability to a CAN controller at speeds up to 1 megabits per second (Mbps).

Designed for operation in harsh environments, the device features cross-wire, over-voltage and loss of ground protection to ±36 V. Also featured are over-temperature protection as well as -7 V to 12 V common-mode range, and tolerance to transients of ±200 V. The transceiver interfaces the single-ended CAN controller with the differential CAN bus found in industrial, building automation, and automotive applications.

Rs, pin 8, selects one of three different modes of operation: high-speed, slope control, or low-power mode. The high-speed mode of operation is selected by connecting pin 8 to ground, allowing the transmitter output transistors to switch as fast as possible with no limitation on the rise and fall slope. The rise and fall slope can be adjusted by connecting a resistor to ground at pin 8; the slope is proportional to the pin's output current. Slope control with an external resistor value of 10 k Ω gives ~ 15 V/us slew rate; 100 k Ω gives ~ 2 V/us slew rate.

If a high logic level is applied to the Rs pin 8, the device enters a low-current standby mode where the driver is switched off and the receiver remains active. The local protocol controller returns the device to the normal mode when it transmits to the bus.

The SN65HVD251 may be used in CAN, DeviceNet[™] or SDS[™] applications with the Texas Instruments' TMS320F241 and TMS320F243 DSPs with CAN 2.0B controllers.



ORDERING INFORMATION

| PART NUMBER | PACKAGE | MARKED AS |
|--------------|--------------------------|-----------|
| SN65HVD251D | 8-pin SOIC (Tube) | VP251 |
| SN65HVD251DR | 8-pin SOIC (Tape & Reel) | VP251 |
| SN65HVD251P | 8-pin DIP | 65HVD251 |



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

DeviceNet is a trademark of Allen-Bradley. SDS is a trademark of Honeywell.





These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

ABSOLUTE MAXIMUM RATINGS

over operating free-air temperature range unless otherwise noted (1)(2)

| | | | SN65HVD251 |
|---|---------------------------------|--------------------|--------------------------------|
| Supply voltage range, V _{CC} | -0.3 V to 7 V | | |
| Voltage range at any bus terminal (| -36 V to 36 V | | |
| Transient voltage per ISO 7637, pulse 1, 2, 3a, 3b CANH, CANL | | ±200 V | |
| Input voltage range, V _I (D, Rs, or R) | -0.3 V to V _{CC} + 0.5 | | |
| Receiver output current, I _O | | | -10 mA to 10 mA |
| | Lluman Rady Madel (3) | CANH, CANL and GND | 14 kV |
| Electrostatic discharge | Human Body Model (3) | All pins | 6 kV |
| | Charged-Device Model (4) | All pins | 1 kV |
| Continuous total power dissipation | | | (see Dissipation Rating Table) |

⁽¹⁾ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- (2) All voltage values, except differential I/O bus voltages, are with respect to network ground terminal.
- 3) Tested in accordance with JEDEC Standard 22, Test Method A114-A.
- (4) Tested in accordance with JEDEC Standard 22, Test Method C101.

ABSOLUTE MAXIMUM POWER DISSIPATION RATINGS

| PACKAGE | CIRCUIT BOARD MODEL | T _A = 25°C POWER RATING | DERATING FACTOR ⁽¹⁾ ABOVE T _A = 25°C | T _A = 85°C POWER RATING | T _A = 125°C POWER RATING |
|----------|------------------------|---------------------------------------|---|---------------------------------------|--|
| SOIC (D) | Low-K ⁽²⁾ | 576 mW | 4.8 mW/°C | 288 mW | 96 mW |
| SOIC (D) | High-K ⁽³⁾ | 924 mW | 7.7 mW/°C | 462 mW | 154 mW |
| DDID (D) | Low-K ⁽²⁾ | 888 mW | 7.4 mW/°C | 444 mW | 148 mW |
| PDIP (P) | High-K ⁽³⁾ | 1212 mW | 10.1 mW/°C | 606 mW | 202 mW |

⁽¹⁾ This is the inverse of the junction-to-ambient thermal resistance when board-mounted and with no air flow.

- (2) In accordance with the Low-K thermal metric definitions of EIA/JESD51-3.
- (3) In accordance with the High-K thermal metric definitions of EIA/JESD51-7.

THERMAL CHARACTERISTICS

| | PARAMETER | TEST CONDITIONS | VALUE | VALUE | | |
|-----------------|---------------------------------------|---|---------|-------|-------|--|
| | | | MIN TYP | MAX | | |
| 0 | lunction to board thermal resistance | D | 78.7 | | °C/M | |
| Θ _{JB} | Junction-to-board thermal resistance | Р | 48.9 | | °C/W | |
| 0 | handler to accept the most market and | D | 44.6 | °C/M | 00044 | |
| ΘJC | Junction-to-case thermal resistance | Р | 66.6 | | °C/W | |
| D | Device rever discipation | V_{CC} = 5 V, Tj = 27 °C, RL = 60Ω , R _S at 0 V, Input to D a 500-kHz 50% duty cycle square wave | | 97.7 | mW | |
| P _D | Device power dissipation | V_{CC} = 5.5 V, Tj = 130°C, RL = 60 Ω , R _S at 0 V, Input to D a 500-kHz 50% duty cycle square wave | | 142 | mW | |
| T_{SD} | Thermal shutdown junction temperature | | 165 | | °C | |



RECOMMENDED OPERATING CONDITIONS

over recommended operating conditions (unless otherwise noted).

| PARAMETER | | MIN NO | M MAX | UNIT |
|---|---|----------------------|---------------------|------|
| Supply voltage, V _{CC} | | 4.5 | 5.5 | V |
| Voltage at any bus terminal (separately or commo | n mode) V _I or V _{IC} | -7 ⁽¹⁾ | 12 | V |
| High-level input voltage, V _{IH} | D input | 0.7 V _{CC} | | V |
| Low-level input voltage, V _{IL} | D input | | 0.3 V _{CC} | V |
| Differential input voltage, V _{ID} | | -6 | 6 | V |
| Input voltage to Rs, V _{I(Rs)} | | 0 | V _{CC} | V |
| Input voltage at Rs for standby, V _{I(Rs)} | | 0.75 V _{CC} | V _{CC} | V |
| Rs wave-shaping resistance | | 0 | 100 | kΩ |
| High lovel output output | Driver | -50 | | A |
| High-level output current, I _{OH} | Receiver | -4 | | mA |
| I am laval autout august I | Driver | | 50 | A |
| Low-level output current, I _{OL} | Receiver | | 4 | mA |
| Operating free-air temperature, T _A | | -40 | 125 | °C |
| handing to see a set up. T | PDIP Package | | 145 | °C |
| Junction temperature, T _j | SOIC Package | | 145 | 30 |

⁽¹⁾ The algebraic convention, in which the least positive (most negative) limit is designated as minimum is used in this data sheet.

DRIVER ELECTRICAL CHARACTERISTICS

over recommended operating conditions (unless otherwise noted).

| | PARAMETE | R | TEST CONDITIONS | MIN | TYP ⁽ | MAX | UNIT |
|---------------------|-------------------------------|-------------------|---|------|------------------|------|------|
| \ / | Bus output voltage | CANH | Figure 1 & Figure 2, | 2.75 | 3.5 | 4.5 | |
| $V_{O(D)}$ | (Dominant) | CANL | D at 0 V Rs at 0 V | 0.5 | | 2 | V |
| V | Bus output voltage | CANH | Figure 1 & Figure 2 , D at 0.7V _{CC} , Rs at 0 V | 2 | 2.5 | 3 | , v |
| V _{O(R)} | (ANL | 2 | 2.5 | 3 | | | |
| $V_{OD(D)}$ | Differential output voltage (| Dominant) | Figure 1, D at 0 V, Rs at 0 V | 1.5 | 2 | 3 | V |
| $V_{OD(D)}$ | Differential output voltage (| Dominant) | Figure 2 & Figure 3, D at 0 V, Rs at 0 V | 1.2 | 2 | 3.1 | V |
| $V_{OD(R)}$ | Differential output voltage (| Recessive) | Figure 1 & Figure 2 , D at 0.7 V _{CC} | -120 | | 12 | mV |
| $V_{OD(R)}$ | Differential output voltage (| Recessive) | D at 0.7 V _{CC} , no load | -0.5 | | 0.05 | V |
| $V_{OC(pp)}$ | Peak-to-peak common-mod | de output voltage | Figure 9, Rs at 0 V | | 600 | | mV |
| I_{IH} | High-level input current, D | Input | D at 0.7 V _{CC} | -40 | | 0 | μΑ |
| $I_{\rm IL}$ | Low-level input current, D I | nput | D at 0.3 V _{CC} | -60 | | 0 | μΑ |
| | | | Figure 11, V _{CANH} at -7 V, CANL Open | -200 | | | |
| 1 | Short-circuit steady-state of | utout current | Figure 11, V _{CANH} at 12 V, CANL Open | | | 2.5 | mA |
| I _{OS(SS)} | Short-circuit steady-state of | atput carrent | Figure 11, V _{CANL} at -7 V, CANH Open | -2 | | | 1117 |
| | | | Figure 11, V _{CANL} at 12 V, CANH Open | | | 200 | |
| Co | Output capacitance | | See receiver input capacitance | | | | |
| I_{OZ} | High-impedance output cur | rent | See receiver input current | | | | |
| $I_{IRs(s)}$ | Rs input current for standby | У | Rs at 0.75 V _{CC} | -10 | | | μΑ |
| I _{IRs(f)} | Rs input current for full spe | ed operation | Rs at 0 V | -550 | | 0 | μΑ |
| | | Standby | Rs at V _{CC} , D at V _{CC} | | | 275 | μΑ |
| I_{CC} | Supply current | Dominant | D at 0 V, 60Ω load, Rs at 0 V | | | 65 | mA |
| | | Recessive | D at V_{CC} , no load, Rs at 0 V | | | 14 | 111/ |

⁽¹⁾ All typical values are at 25°C and with a 5-V supply.



DRIVER SWITCHING CHARACTERISTICS

over recommended operating conditions (unless otherwise noted).

| | PARAMETER | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|--------------------|---|--|-----|------|------|------|
| | | Figure 4, Rs at 0 V | | 40 | 70 | |
| t_{pLH} | Propagation delay time, low-to-high-level output | Figure 4, Rs with 10 $k\Omega$ to ground | | 90 | 125 | |
| | | Figure 4, Rs with 100 $k\Omega$ to ground | | 500 | 800 | |
| | | Figure 4, Rs at 0 V | | 85 | 125 | |
| t_{pHL} | Propagation delay time, high-to-low-level output | Figure 4, Rs with 10 $k\Omega$ to ground | | 200 | 260 | |
| | | Figure 4, Rs with 100 k Ω to ground | | 1150 | 1450 | |
| | | Figure 4, Rs at 0 V | | 45 | 85 | |
| t _{sk(p)} | Pulse skew (t _{pHL} - t _{pLH}) | Figure 4, Rs with 10 $k\Omega$ to ground | | 110 | 180 | ns |
| | | Figure 4, Rs with 100 k Ω to ground | | 650 | 900 | |
| t _r | Differential output signal rise time | Figure 4 Do at 0.V | 35 | | 100 | |
| t _f | Differential output signal fall time | Figure 4, Rs at 0 V | 35 | | 100 | |
| t _r | Differential output signal rise time | Figure 4 De with 40 kg to ground | 100 | | 250 | |
| t _f | Differential output signal fall time | Figure 4, Rs with 10 kΩ to ground | 100 | | 250 | |
| t _r | Differential output signal rise time | Figure 4. Do with 400 looks around | 600 | | 1550 | |
| t _f | Differential output signal fall time | Figure 4, Rs with 100 kΩ to ground | 600 | | 1550 | |
| t _{en} | Enable time from standby to dominant | Figure 8 | | | 0.5 | μs |

RECEIVER ELECTRICAL CHARACTERISTICS

over recommended operating conditions (unless otherwise noted).

| | PARAME | TER | TEST CONDITION | ONS | MIN | TYP | MAX | UNIT |
|------------------|---|--|---|--|------------|-----|------------|------|
| V_{IT+} | Positive-going input threshold v | roltage | | | | 750 | 900 | |
| V _{IT-} | Negative-going input threshold | voltage | Rs at 0 V, (See Table 1) | | 500 | 650 | | mV |
| V_{hys} | Hysteresis voltage (V _{IT+} - V _{IT-}) | | | | | 100 | | |
| V _{OH} | High-level output voltage | | Figure 6, I _O = -4mA | | 0.8 Vcc | | | V |
| V _{OL} | Low-level output voltage | | Figure 6, I _O = 4mA | | | | 0.2 Vcc | V |
| | | | CANH or CANL at 12 V | | | | 600 | |
| | Bus input current | | CANH or CANL at 12 V, V _{CC} at 0 V | Other bus pin at 0 V, Rs at 0 V, D at 0.7 | | | 715 | |
| I _I | | | CANH or CANL at -7 V | | -460 | | | μA |
| | | CANH or CANL at -7 V, V _{CC} at 0 V | | | | | | |
| C _I | Input capacitance, (CANH or C | ANL) | Pin-to-ground, $V_I = 0.4 \text{ si}$ 0.5 V, D at 0.7 V _{CC} | n (4E6πt) + | | 20 | | pF |
| C _{ID} | Differential input capacitance | | Pin-to-pin, $V_I = 0.4 \sin (4 \text{ V}, \text{ D at } 0.7 \text{ V}_{CC}$ | E6πt) + 0.5 | | 10 | | pF |
| R_{ID} | Differential input resistance | | D at 0.7 V _{CC} , Rs at 0 V | | 40 | | 100 | kΩ |
| R _{IN} | Input resistance, (CANH or CAI | NL) | D at 0.7 V _{CC} , Rs at 0 V | | 20 | | 50 | kΩ |
| | | Standby | Rs at V _{CC} , D at V _{CC} | | | | 275 | μA |
| I_{CC} | Supply current | Dominant | D at 0 V, 60Ω Load, Rs a | t 0 V | | | 65 | mA |
| | | Recessive | D at V _{CC} , No Load, Rs at | 0 V | | | 14 | IIIA |



RECEIVER SWITCHING CHARACTERISTICS

over recommended operating conditions (unless otherwise noted).

| | PARAMETER | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|--------------------|---|----------------------------------|-----|-----|-----|------|
| t _{pLH} | Propagation delay time, low-to-high-level output | | | 35 | 50 | |
| t _{pHL} | Propagation delay time, high-to-low-level output | | | 35 | 50 | |
| t _{sk(p)} | Pulse skew (t _{pHL} - t _{pLH}) | Figure 6 | | | 20 | no |
| t _r | Output signal rise time | | | 2 | 4 | ns |
| t _f | Output signal fall time | | | 2 | 4 | |
| t _{p(sb)} | Propagation delay time in standby | Figure 12, Rs at V _{CC} | | | 500 | |

VREF-PIN CHARACTERISTICS

over recommended operating conditions (unless otherwise noted).

| | PARAMETER | TEST CONDITIONS | MIN | TYP MAX | UNIT |
|----|--------------------------|---------------------------------|----------------------|----------------------|------|
| V | Deference cutout veltage | -5 μA < I _O < 5 μA | 0.45 V _{CC} | 0.55 V _{CC} | V |
| VO | Reference output voltage | -50 μA < I _O < 50 μA | 0.4 V _{CC} | 0.6 V _{CC} | V |

DEVICE SWITCHING CHARACTERISTICS

over recommended operating conditions (unless otherwise noted).

| | PARAMETER | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|--------------------|--|--|-----|------|------|------|
| | | Figure 10, Rs at 0 V | | 60 | 100 | |
| t _{loop1} | Total loop delay, driver input to receiver output, recessive to dominant | Figure 10, Rs with 10 $k\Omega$ to ground | | 100 | 150 | ns |
| | output, recessive to definition | Figure 10, Rs with 100 kΩ to ground | | 440 | 800 | |
| | | Figure 10, Rs at 0 V | | 115 | 150 | |
| t _{loop2} | Total loop delay, driver input to receiver output, dominant to recessive | Figure 10, Rs with 10 k Ω to ground | | 235 | 290 | ns |
| | output, dominant to recessive | Figure 10, Rs with 100 kΩ to ground | | 1070 | 1450 | |
| t _{loop2} | Total loop delay, driver input to receiver output, dominant to recessive | Figure 10, Rs at 0 V, V _{CC} from 4.5 V to 5.1 V, | | 105 | 145 | ns |

PARAMETER MEASUREMENT INFORMATION

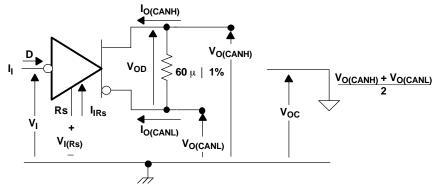


Figure 1. Driver Voltage, Current, and Test Definition



PARAMETER MEASUREMENT INFORMATION (continued)

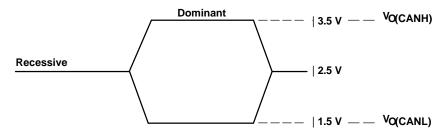


Figure 2. Bus Logic State Voltage Definitions

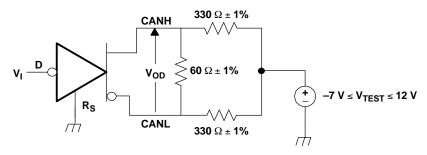


Figure 3. Driver V_{OD}

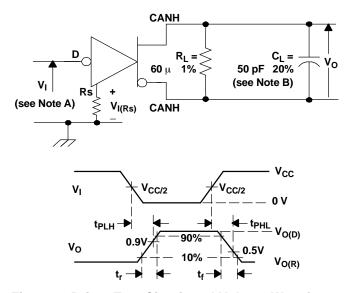


Figure 4. Driver Test Circuit and Voltage Waveforms

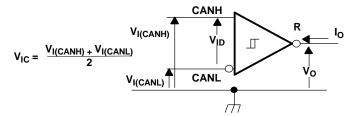
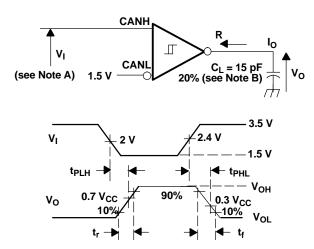


Figure 5. Receiver Voltage and Current Definitions

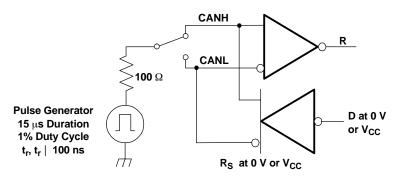


PARAMETER MEASUREMENT INFORMATION (continued)



- A. The input pulse is supplied by a generator having the following characteristics: PRR \leq 125 kHz, 50% duty cycle, $t_i \leq$ 6ns, t_i
- B. C₁ includes instrumentation and fixture capacitance within ±20%.

Figure 6. Receiver Test Circuit and Voltage Waveforms



A. This test is conducted to test survivability only. Data stability at the R output is not specified.

Figure 7. Test Circuit, Transient Over-Voltage Test

Table 1. Receiver Characteristics Over Common Mode Voltage

| INF | TUT | MEASURED | OUT | ГРИТ |
|-------------------|-------------------|-----------------|-----|-----------------|
| V _{CANH} | V _{CANL} | V _{ID} | | R |
| 12 V | 11.1 V | 900 mV | L | |
| -6.1 V | -7 V | 900 mV | L | |
| -1 V | -7 V | 6 V | L | V _{OL} |
| 12 V | 6 V | 6 V | L | |
| -6.5 V | -7 V | 500 mV | Н | |
| 12 V | 11.5 V | 500 mV | Н | |
| -7 V | -1 V | 6 V | Н | V _{OH} |
| 6 V | 12 V | 6 V | Н | |
| open | open | Х | Н | |



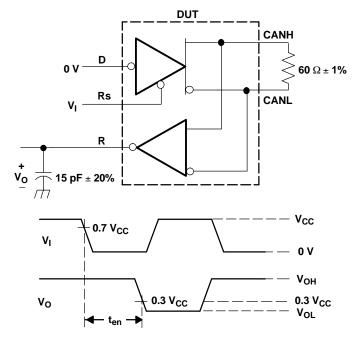
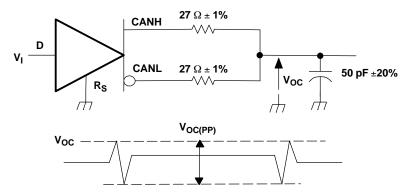


Figure 8. t_{en} Test Circuit and Voltage Waveforms



A. The input pulse is supplied by a generator having the following characteristics: PRR \leq 125 kHz, 50% duty cycle, $t_{\rm f} \leq$ 6ns, $t_{\rm f$

Figure 9. Peak-to-Peak Common Mode Output Voltage



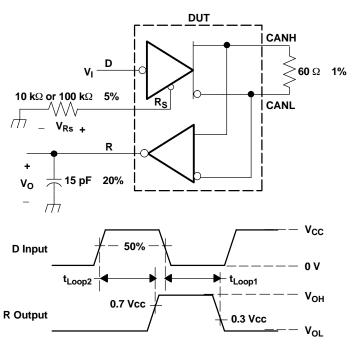


Figure 10. t_{LOOP} Test Circuit and Voltage Waveforms

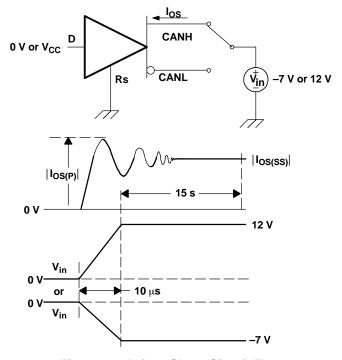
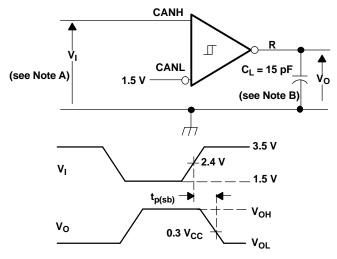


Figure 11. Driver Short-Circuit Test





- A. The input pulse is supplied by a generator having the following characteristics: PRR \leq 125 kHz, 50% duty cycle, $t_r \leq$ 6ns, $t_l \leq$ 6ns, $Z_Q = 50\Omega$.
- B. CL includes instrumentation and fixture capacitance within ±20%.

Figure 12. Receiver Propagation Delay in Standby Test Circuit and Waveform

DEVICE INFORMATION 5 V R2 1% R1 1% **CANH** R V_{ID} CANL Vac R1 1% V_{I} R2 1% V_{ID} R1 R2 500 mV 50 Ω $\mathbf{450}\;\Omega$ 900 mV **50** Ω **227** Ω

A. All input pulses are supplied by a generator having the following characteristics: f < 1.5 MHz, $T_A = 25$ °C, $V_{CC} = 5.0$ V.

Figure 13. Common-Mode Input Voltage Rejection Test



DEVICE INFORMATION (continued) FUNCTION TABLES

Table 2. DRIVER

| INPUTS | Valtage of B. V | OUT | DUC CTATE | | |
|--------|---|------|-----------|-----------|--|
| D | Voltage at R _s , V _{Rs} | CANH | CANL | BUS STATE | |
| L | V _{Rs} < 1.2 V | Н | L | Dominant | |
| Н | V _{Rs} < 1.2 V | Z | Z | Recessive | |
| Open | X | Z | Z | Recessive | |
| X | V _{Rs} > 0.75 V _{CC} | Z | Z | Recessive | |

Table 3. RECEIVER

| DIFFERENTIAL INPUTS [V _{ID} = V(CANH) - V(CANL)] | OUTPUT R ⁽¹⁾ |
|---|-------------------------|
| V _{ID} ≥ 0.9 V | L |
| 0.5V < V _{ID} < 0.9 V | ? |
| V _{ID} ≤ 0.5 V | Н |
| Open | Н |

⁽¹⁾ H = high level; L = low level; X = irrelevant; ? = indeterminate; Z = high impedance



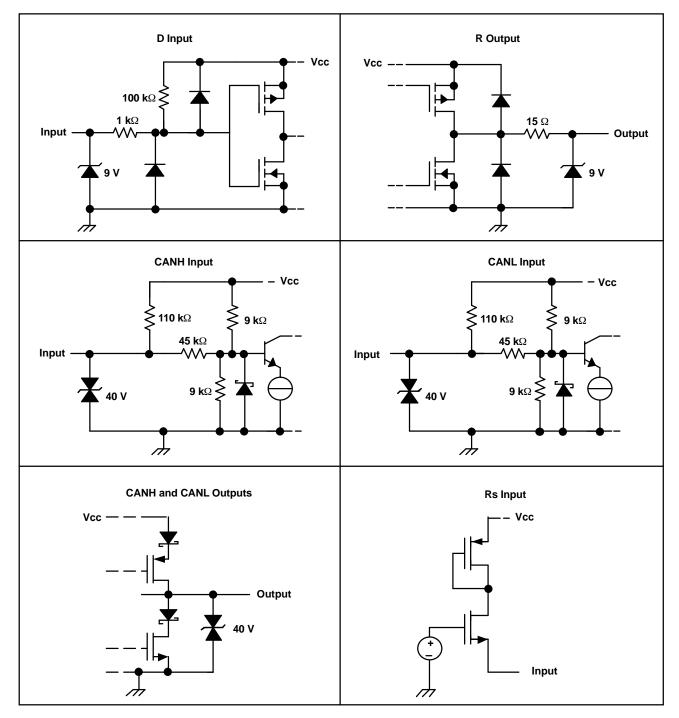


Figure 14. Equivalent Input and Output Schematic Diagrams



TYPICAL CHARACTERISTICS

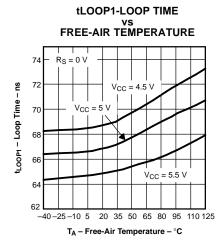


Figure 15.

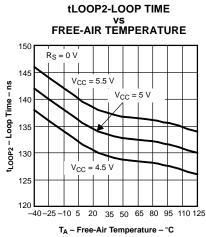


Figure 16.

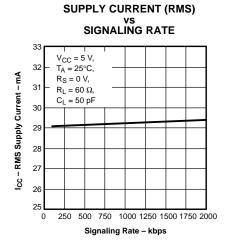


Figure 17.

DRIVER LOW-LEVEL OUTPUT CURRENT vs LOW-LEVEL OUTPUT VOLTAGE

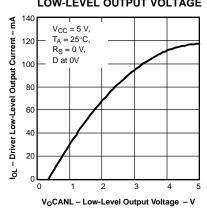


Figure 18.

DRIVER HIGH-LEVEL OUTPUT CURRENT VS HIGH-LEVEL OUTPUT VOLTAGE 80 Vcc = 5 V.

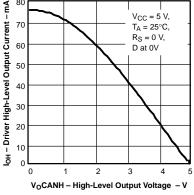


Figure 19.

DOMINANT DIFFERENTIAL OUTPUT VOLTAGE vs FREE-AIR TEMPERATURE

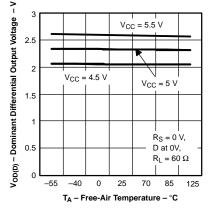


Figure 20.

DRIVER OUTPUT CURRENT vs SUPPLY VOLTAGE

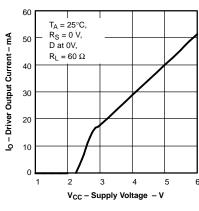


Figure 21.

DIFFERENTIAL OUTPUT FALL TIME VS SLOPE RESISTANCE (RS)

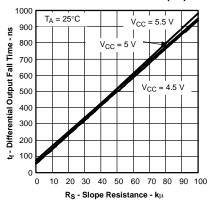


Figure 22.

INPUT RESISTANCE MATCHING vs FREE-AIR TEMPERATURE

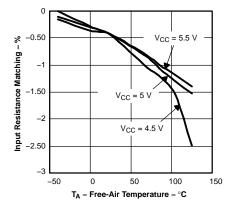


Figure 23.



APPLICATION INFORMATION

The basics of bus arbitration require that the receiver at the sending node designate the first bit as dominant or recessive after the initial wave of the first bit of a message travels to the most remote node on a network and back again. Typically, this *sample* is made at 75% of the bit width, and within this limitation, the maximum allowable signal distortion in a CAN network is determined by network electrical parameters.

Factors to be considered in network design include the 5 ns/m propagation delay of typical twisted-pair bus cable; signal amplitude loss due to the loss mechanisms of the cable; and the number, length, and spacing of drop-lines (stubs) on a network. Under strict analysis, variations among the different oscillators in a system must also be accounted for with adjustments in signaling rate and stub & bus length. Table 4 lists the maximum signaling rates achieved with the SN65HVD251 in high-speed mode with several bus lengths of category-5, shielded twisted-pair (CAT 5 STP) cable.

Table 4. Maximum Signaling Rates for Various Cable Lengths

| BUS LENGTH (m) | SIGNALING RATE (kbps) |
|----------------|-----------------------|
| 30 | 1000 |
| 100 | 500 |
| 250 | 250 |
| 500 | 125 |
| 1000 | 62.5 |

The ISO 11898 standard specifies a maximum bus length of 40 m and maximum stub length of 0.3 m with a maximum of 30 nodes. However, with careful design, users can have longer cables, longer stub lengths, and many more nodes on a bus. (Note: Non-standard application may come with a trade-off in signaling rate.) A bus with a large number of nodes requires a transceiver with high input impedance such as the HVD251.

The Standard specifies the interconnect to be a single twisted-pair cable (shielded or unshielded) with $120-\Omega$ characteristic impedance (Zo). Resistors equal to the characteristic impedance of the line terminate both ends of the cable to prevent signal reflections. Unterminated drop-lines connect nodes to the bus and should be kept as short as possible to minimize signal reflections.

Connectors, while not specified by the ISO 11898 standard, should have as little effect as possible on standard operating parameters such as capacitive loading. Although unshielded cable is used in many applications, data transmission circuits employing CAN transceivers are usually used in applications requiring a rugged interconnection with a wide common-mode voltage range. Therefore, shielded cable is recommended in these electronically harsh environments, and when coupled with the –2-V to 7-V common-mode range of tolerable ground noise specified in the standard, helps to ensure data integrity. The HVD251 extends data integrity beyond that of the standard with an extended –7-V to 12-V range of common-mode operation.

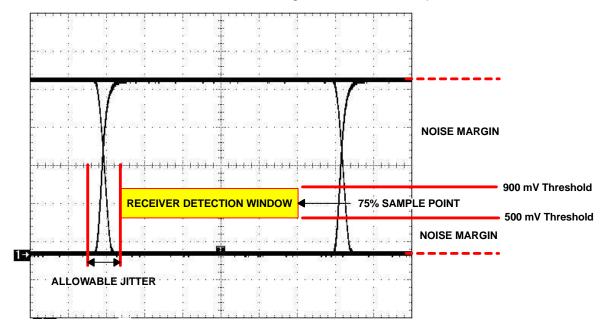


Figure 24. Typical CAN Differential Signal Eye-Pattern



An eye pattern is a useful tool for measuring overall signal quality. As displayed in Figure 24, the differential signal changes logic states in two places on the display, producing an *eye*. Instead of viewing only one logic crossing on the scope, an entire *bit* of data is brought into view. The resulting eye pattern includes all effects of systemic and random distortion, and displays the time during which a signal may be considered valid.

The height of the eye above or below the receiver threshold voltage level at the sampling point is the noise margin of the system. Jitter is typically measured at the differential voltage zero-crossing during the logic state transition of a signal. Note that jitter present at the receiver threshold voltage level is considered by some to be a more effective representation of the jitter at the input of a receiver.

As the sum of skew and noise increases, the eye closes and data is corrupted. Closing the width decreases the time available for accurate sampling, and lowering the height enters the 900 mV or 500 mV threshold of a receiver.

Different sources induce noise onto a signal. The more obvious noise sources are the components of a transmission circuit themselves; the signal transmitter, traces & cables, connectors, and the receiver. Beyond that, there is a termination dependency, cross-talk from clock traces and other proximity effects, VCC & ground bounce, and electromagnetic interference from near-by electrical equipment.

The balanced receiver inputs of the HVD251 mitigate most sources of signal corruption, and when used with a quality shielded twisted-pair cable, help ensure data integrity.

Typical Application

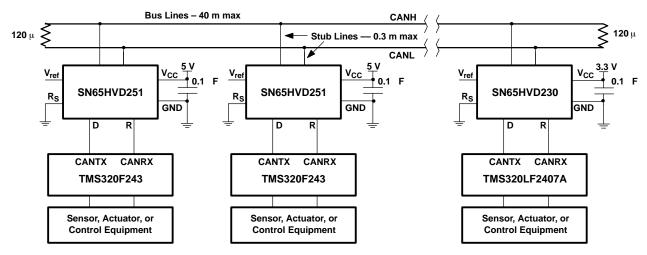


Figure 25. Typical HVD251 Application





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PACKAGING INFORMATION

| Orderable Device | Status ⁽¹⁾ | Package Type | Package Drawing | Pins | Package Qty | e Eco Plan ⁽²⁾ | Lead/Ball Finish | MSL Peak Temp ⁽³⁾ |
|------------------|-----------------------|-----------------|--------------------|------|----------------|---------------------------|------------------|------------------------------|
| SN65HVD251D | ACTIVE | SOIC | D | 8 | 75 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-1-260C-UNLIM |
| SN65HVD251DG4 | ACTIVE | SOIC | D | 8 | 75 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-1-260C-UNLIM |
| SN65HVD251DR | ACTIVE | SOIC | D | 8 | 2500 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-1-260C-UNLIM |
| SN65HVD251DRG4 | ACTIVE | SOIC | D | 8 | 2500 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-1-260C-UNLIM |
| SN65HVD251P | ACTIVE | PDIP | Р | 8 | 50 | Pb-Free (RoHS) | CU NIPDAU | N / A for Pkg Type |
| SN65HVD251PE4 | ACTIVE | PDIP | Р | 8 | 50 | Pb-Free (RoHS) | CU NIPDAU | N / A for Pkg Type |

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

(3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

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OTHER QUALIFIED VERSIONS OF SN65HVD251:

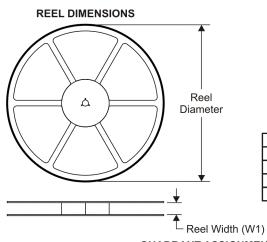
Automotive: SN65HVD251-Q1

NOTE: Qualified Version Definitions:

• Automotive - Q100 devices qualified for high-reliability automotive applications targeting zero defects



TAPE AND REEL INFORMATION





| Α | 0 | Dimension designed to accommodate the component width |
|----|---|---|
| В | 0 | Dimension designed to accommodate the component length |
| | | Dimension designed to accommodate the component thickness |
| ٧ | ٧ | Overall width of the carrier tape |
| ГР | 1 | Pitch between successive cavity centers |

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

| Device | | Package Drawing | | | Reel Diameter (mm) | Reel Width W1 (mm) | A0 (mm) | B0 (mm) | K0 (mm) | P1 (mm) | W (mm) | Pin1 Quadrant |
|--------------|------|--------------------|---|------|--------------------------|--------------------------|---------|---------|---------|------------|-----------|------------------|
| SN65HVD251DR | SOIC | D | 8 | 2500 | 330.0 | 12.4 | 6.4 | 5.2 | 2.1 | 8.0 | 12.0 | Q1 |





*All dimensions are nominal

| | Device | Package Type | Package Drawing | Pins | SPQ | Length (mm) | Width (mm) | Height (mm) |
|---|--------------|--------------|-----------------|------|------|-------------|------------|-------------|
| I | SN65HVD251DR | SOIC | D | 8 | 2500 | 340.5 | 338.1 | 20.6 |

D (R-PDSO-G8)

PLASTIC SMALL-OUTLINE PACKAGE



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed .006 (0,15) per end.
- Body width does not include interlead flash. Interlead flash shall not exceed .017 (0,43) per side.
- E. Reference JEDEC MS-012 variation AA.



P (R-PDIP-T8)

PLASTIC DUAL-IN-LINE



NOTES: A. All linear dimensions are in inches (millimeters).

- B. This drawing is subject to change without notice.
- C. Falls within JEDEC MS-001

For the latest package information, go to $http://www.ti.com/sc/docs/package/pkg_info.htm$

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